



# MULTILAYER CERAMIC CAPACITORS High Q / Low ESR Series (HH) 0402, 0603 & 0805 Sizes NP0 Dielectric RoHS Compliance

\*Contents in this sheet are subject to change without prior notice.



#### **1. INTRODUCTION**

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

WTC HH series MLCC is used at high frequencies generally have a small temperature coefficient of capacitance, typical within the  $\pm 30$  ppm/°C required for NP0 (C0G) classification and have excellent conductivity internal electrode. Thus, WTC HH series MLCC will be with the feature of low ESR and high Q characteristics.

#### 2. FEATURES

- a. High Q and low ESR performance at high frequency.
- b. Quality improvement of telephone calls for low power loss and better performance.

#### **3. APPLICATIONS**

- a. Mobile telecommunication: Mobile phone, WLAN.
- b. RF module: Power amplifier, VCO.
- c. Tuners.

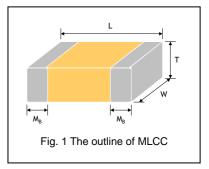
## 4. HOW TO ORDER

<u>HH</u>	<u>15</u>	N	<u>100</u>	G	<u>500</u>	<u>C</u>	Ī
<u>Series</u>	Size	Dielectric	<u>Capacitance</u>	Tolerance	Rated voltage	Termination	Packaging
HH=High Q/ Low ESR	<b>15</b> =0402 (1005) <b>18</b> =0603 (1608) <b>21</b> =0805 (2012)	<b>N</b> =NP0 (C0G)	Two significant digits followed by no. of zeros. And R is in place of decimal point.	<b>B</b> =±0.1pF <b>C</b> =±0.25pF <b>D</b> =±0.5pF <b>F</b> =±1% <b>G</b> =±2%	Two significant digits followed by no. of zeros. And R is in place of decimal point.	L=Ag/Ni/Sn C=Cu/Ni/Sn	T=7" reeled G=13" reeled
			eg.: R47=0.47pF 0R5=0.5pF 1R0=1.0pF 100=10x10 <sup>0</sup> =10pF	<b>J</b> =±5%	160=16 VDC 250=25 VDC 500=50 VDC 101=100 VDC 201=200 VDC 251=250 VDC 501=500 VDC 631=630 VDC		



## **5. EXTERNAL DIMENSIONS**

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Symbol		Remark	М <sub>в</sub> (mm)	
0402 (1005)	1.00±0.05	0.50±0.05	0.50±0.05	N	#	0.25 +0.05/-0.10	
	1.60±0.10	0.80±0.10	0.80±0.07	0.80±0.07 S			
0603 (1608)	1.60 +0.15/-0.10	0.80 +0.15/-0.10	0.80 +0.15/-0.10	x		0.40±0.15	
			0.60±0.10	A			
0805 (2012)	2.00±0.15	1.25±0.10	0.80±0.10	В		0.50±0.20	
			1.25±0.10	D	#		



# Reflow soldering only is recommended.

# **6. GENERAL ELECTRICAL DATA**

Dielectric	NPO				
Size	0402, 0603, 0805				
	0402: 0.5pF to 470pF**				
Capacitance*	0603: 0.5pF to 3300pF				
	0805: 0.5pF to 390pF				
	Cap≤5pF: B (±0.1pF), C (±0.25pF)				
Capacitance tolerance	5pF <cap<10pf: (±0.25pf),="" (±0.5pf)<="" c="" d="" td=""></cap<10pf:>				
	Cap≥10pF: F (±1%), G (±2%), J (±5%)				
Rated voltage (WVDC)	16V, 25V, 50V, 100V, 200V, 250V, 500V, 630V				
Q*	Cap<30pF: Q≥400+20C				
Υ Υ	Cap≥30pF: Q≥1000				
Insulation resistance at Ur	≥10GΩ or RxC≥100Ω-F whichever is smaller.				
Operating temperature	-55 to +125℃				
Capacitance change	±30ppm				
Termination	Ni/Sn (lead-free termination)				

\* Measured at the conditions of 25°C ambient temper ature and 30~70% related humidity.

Apply 1.0±0.2Vrms, 1.0MHz±10% for Cap<1000pF and 1.0±0.2Vrms, 1.0kHz±10% for Cap>1000pF.

\*\* 0402, Capacitance <0.5pF: On request.



## **7. CAPACITANCE RANGE**

	DIELECTRIC NP0													
	SIZE		0402			06	03				80	05		
	Rated Voltage	16	25	50	16	25	50	100	50	100	200	250	500	630
	0.5pF (0R5)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.6pF (0R6)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.7pF (0R7)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.8pF (0R8)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.9pF (0R9)	N^	N^	N^	S^	S^	S^	S^	В	В				
	1.0pF (1R0)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	1.2pF (1R2)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	1.5pF (1R5)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	1.8pF (1R8)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	2.2pF (2R2)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	2.7pF (2R7)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	3.3pF (3R3)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	3.9pF (3R9)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	4.7pF (4R7)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	5.6pF (5R6)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	6.8pF (6R8)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	8.2pF (8R2)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	10pF (100)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
	12pF (120)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
	15pF (150)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
	18pF (180)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
	22pF (220)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
nce	27pF (270)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
Capacitance	33pF (330)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
pac	39pF (390)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
Ca	47pF (470)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
	56pF (560)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
	68pF (680)	N	N	N	S	S	S	S	В	В	В	В	В	В
	82pF (820)	N	N	N	S	S	S	S	В	В	В	В	В	В
	100pF (101)	Ν	N	Ν	S	S	S	S	В	В	В	В	В	В
	120pF (121)	N	N	Ν	S	S	S	S	D	D	D	D	D	D
	150pF (151)	N	N	N	S	S	S	S	D	D	D	D	D	D
	180pF (181)	N	N	N	S	S	S	S			D	D	D	D
	220pF (221)	N	N	N	S	S	S	S			D	D	D	D
	270pF (271)	N	N	N	S	S	S	S			D	D	D	D
	330pF (331)	N	N	N	S	S	S	S			D	D	D	D
	390pF (391)	N	N	N	S	S	S	S			D	D	D	D
	470pF (471)	N	N	N	S	S	S	S						
	560pF (561)				S	S	S	S						
	680pF (681)				S	S	S	S						
	820pF (821)				S	S	S	S	<u> </u>					
	1,000pF (102)				S	S	S	S						
	1,200pF (122)				X	X	X							
	1,500pF (152)				X	X	X							
	1,800pF (182)				X	X	X			<u> </u>				
	2,200pF (222) 2,700pF (272)				X X	X X	X X							
					X	X	X		[					
	3,300pF (332)						^							

1. The letter in cell is expressed the symbol of product thickness.

2. The letter in cell with "^" mark is expressed product with Ag/Ni/Sn terminations.

3. 0402, Capacitance <0.5pF: On request.

4. For more information about products with special capacitance or other data, please contact WTC local representative.



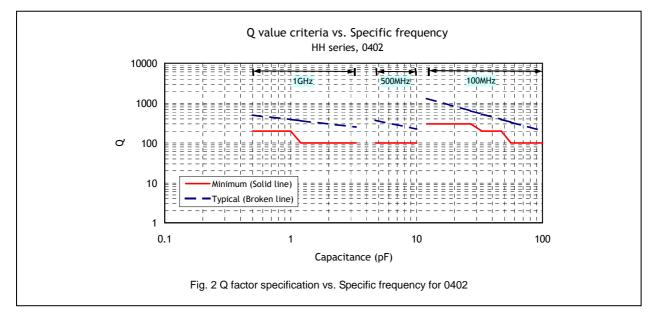
## **8. PACKAGING DIMENSION AND QUANTITY**

Size	Thickness (mm)/Syml	Pape	r tape	Plastic tape		
5126		7" reel	13" reel	7" reel	13" reel	
0402	0.50±0.05	N	10K	50K		
0603	0.80±0.07	S	4K	15K		
0603	0.80 +0.15/-0.10	Х	45	IDK		
	0.60±0.10	A	414	451		
0805	0.80±0.10	В	4k	15k		
	1.25±0.10	D			3k	10k

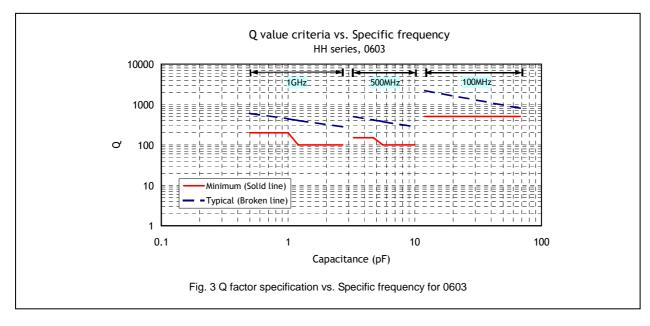
Unit: pieces

## 9. ELECTRICAL CHARACTERISTICS

#### Q factor specification vs. Specific frequency

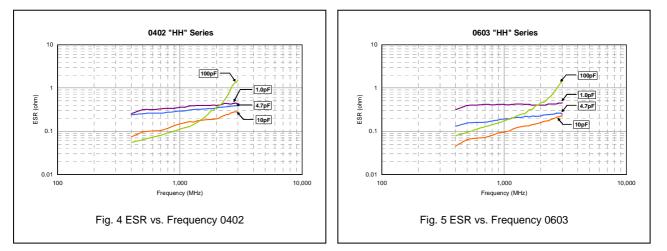


#### Q factor specification vs. Specific frequency

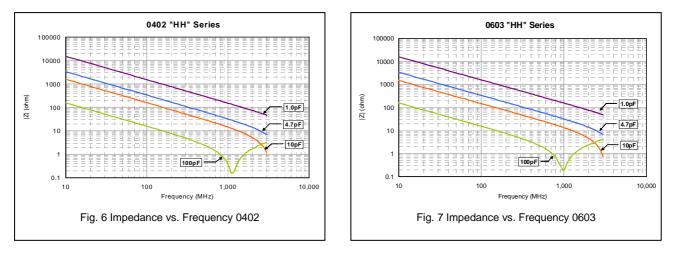




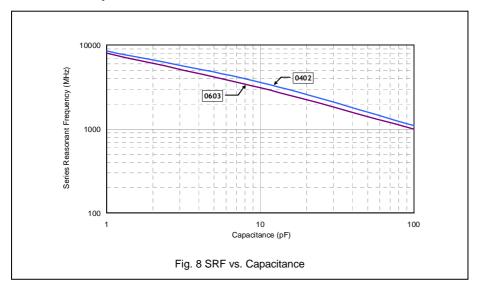
#### Typical ESR vs. Frequency



#### Typical Impedance vs. Frequency



#### SRF vs. Capacitance



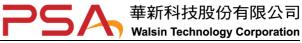


# **10. RELIABILITY TEST CONDITIONS AND REQUIREMENTS**

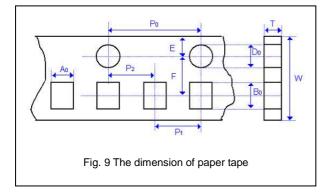
No.	ltem	Test Conditions	Requirements
1.	Visual and		* No remarkable defect.
	Mechanical		* Dimensions to conform to individual specification sheet.
2.	Capacitance	Cap≤1000pF, 1.0±0.2Vrms, 1MHz±10%	* Shall not exceed the limits given in the detailed spec.
3.	Q/ D.F.	Cap>1000pF, 1.0±0.2Vrms, 1KHz±10%	* NP0: Cap≥30pF, Q≥1000; Cap<30pF, Q≥400+20C
	(Dissipation	At 25℃ ambient temperature.	
	Factor)		
4.	Dielectric	* To apply voltage: ( ≤100V ) 250% of rated voltage.	* No evidence of damage or flash over during test.
	Strength	* Duration: 1 to 5 sec.	
		* Charge and discharge current less than 50mA.	
		* To apply voltage:	
		200V~300V ≥2 times VDC	
		500V~999V ≥1.5 times VDC	
		* Cut-off, set at 10mA	
		* TEST= 15 sec.	
		* RAMP=0	
5.	Insulation	Rated voltage:<200V	≥10GΩ
	Resistance	To apply rated voltage for max. 120 sec.	
		Rated voltage:200~630V	≥10GΩ or RxC≥100Ω-F whichever is smaller
		To apply rated voltage (500V max.) for 60 sec.	
6.	Temperature	With no electrical load.	* Capacitance change: within ±30ppm/℃
	Coefficient	Operating temperature: -55~125℃ at 25℃	
7.	Adhesive	* Pressurizing force :	* No remarkable damage or removal of the terminations.
	Strength of	5N (≤0603) and 10N (>0603)	
	Termination	* Test time: 10±1 sec.	
8.	Vibration	* Vibration frequency: 10~55 Hz/min.	* No remarkable damage.
	Resistance	* Total amplitude: 1.5mm	* Cap change and Q/D.F.: To meet initial spec.
		* Test time: 6 hrs. (Two hrs each in three mutually	
		perpendicular directions.)	
		* Measurement to be made after keeping at room temp. for	
		24±2 hrs.	
9.	Solderability	* Solder temperature: 235±5℃	95% min. coverage of all metalized area.
		* Dipping time: 2±0.5 sec.	
10.	Bending Test	* The middle part of substrate shall be pressurized by means	* No remarkable damage.
		of the pressurizing rod at a rate of about 1 mm per second until	
		the deflection becomes 1 mm and then the pressure shall be	(This capacitance change means the change of capacitance under
		maintained for 5±1 sec.	specified flexure of substrate from the capacitance measured before
		* Measurement to be made after keeping at room temp. for	the test.)
44	<b>D</b>	24±2 hrs.	
11.	Resistance to	* Solder temperature: 260±5℃	* No remarkable damage.
	Soldering Heat	* Dipping time: 10±1 sec	* C/D E L B and dialoctric strength: To most initial requirements
		* Preheating: 120 to 150°C for 1 minute before immerse the	Q/D.F., I.R. and dielectric strength: To meet initial requirements.
		capacitor in a eutectic solder.	* 25% max. leaching on each edge.
		* Before initial measurement (Class II only): Perform	
		$150+0/-10^{\circ}$ for 1 hr and then set for $24\pm2$ hrs at room temp.	
		* Measurement to be made after keeping at room temp. for	
		24±2 hrs.	<u> </u>

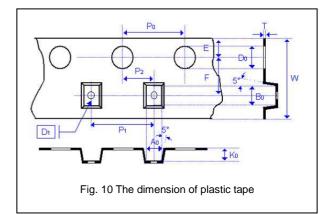


No.	ltem	Test Condition					Requirements		
12.	Temperature Cycle	* Cor time.	nduct	t the five cycles according to th	e temperatures a	nd	* No remarkable damage.		
	Cycle	S	tep	Temp. (°C)	Time (min.)		Cap change : within $\pm 2.5\%$ or $\pm 0.25pF$ whichever is larger.		
			1	Min. operating temp. +0/-3	30±3		* Q/D.F., I.R. and dielectric strength: To meet initial requirements.		
			2	Room temp.	2~3				
			3	Max. operating temp. +3/-0	30±3				
			4	Room temp.	2~3				
		* Bef	ore ir	nitial measurement (Class II or	nly): Perform				
		150+	0/-10	℃ for 1 hr and then set for 24:	±2 hrs at r oom te	mp.			
		* Mea	asure	ement to be made after keeping	g at room temp. f	or			
		24±2	hrs.						
13.	Humidity	* Tes	t tem	ıp.: 40±2℃			* No remarkable damage.		
	(Damp Heat)	* Hur	nidity	/: 90~95% RH					
	Steady State	* Tes	t time	e: 500+24/-0hrs.			* Cap change: within ±5.0% or ±0.5pF whichever is larger.		
		*Before initial measurement (Class II only): Perform					* Q/D.F. value:		
		150+	0/-10	℃ for 1 hr and then set for 24:	±2 hrs at r oom te	NP0: Cap≥30pF, Q≥350; 10pF≤Cap<30pF, Q≥275+2.5C			
		* Mea	asure	ement to be made after keeping	g at room temp. f	Cap<10pF; Q≥200+10C			
		24±2 hrs.					* I.R.: ≥1GΩor RxC≥50Ω-F whichever is smaller.		
14.	Humidity	* Test temp.: 40±2℃					* No remarkable damage.		
	(Damp Heat)	* Hur	nidity	/: 90~95%RH			* Cap change: within ±7.5% or ±0.75pF whichever is larger.		
	Load	* Tes	t time	e: 500+24/-0 hrs.		* Q/D.F. value:			
		* To a	apply	voltage : rated voltage (Max.	500V)	NP0: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller.			
		* Bef	ore ir	nitial measurement (Class II or	nly): To apply test				
		volta	ge fo	r 1hr at 40℃ and then set for 2	4±2 hrs at room	emp.			
		* Mea	asure	ement to be made after keeping	g at room temp. f	or			
		24±2	2 hrs						
15.	High	* Tes	t tem	ip.:			* No remarkable damage.		
	Temperature	NP	0: 12	5±3℃			* Cap change: within ±3.0% or ±0.3pF whichever is larger.		
	Load	* To a	apply	voltage:			* Q/D.F. value:		
	(Endurance)	(1) <	500V	: 200% of rated voltage.			NP0: Cap≥30pF, Q≥350		
		(2) 50	00V:	150% of rated voltage.			10pF≤Cap<30pF, Q≥275+2.5C		
		(3) ≥6	630V	: 120% of rated voltage.		Cap<10pF, Q≥200+10C			
		* Tes	t time	e: 1000+24/-0 hrs.			* I.R.: $\geq 1G\Omega$ or RxC $\geq 50\Omega$ -F whichever is smaller.		
		*Befc	ore in	itial measurement (Class II on	ly): To apply test				
				r 1hr at test temp. and then se					
		temp	-		u				
				ment to be made after keeping	at room temp fo	r			
		24±2			, at room tomp. It	•			
		2+12	111.5						
		:							

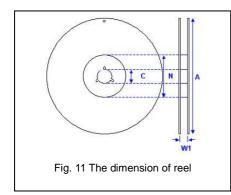


#### Tape & reel dimensions

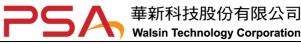


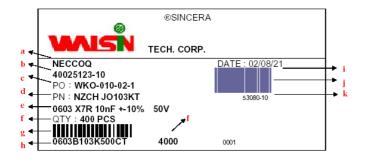


Size	0402	0603		0805	
Thickness	Ν	S, X	Α	В	C, D, I
A	0.62±0.05	1.02±0.05	1.50±0.10	1.50±0.10	<1.57
Bo	1.12±0.05	1.80±0.05	2.30±0.10	2.30±0.10	<2.40
Т	0.60±0.05	0.95±0.05	0.75±0.05	0.95±0.05	0.23±0.05
K₀	-	-	-	-	<2.50
w	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10
Po	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10
10xP₀	40.0±0.10	40.0±0.10	40.0±0.10	40.0±0.10	40.0±0.10
<b>P</b> <sub>1</sub>	2.00±0.05	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10
P <sub>2</sub>	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05
Do	1.55±0.05	1.55±0.05	1.55±0.05	1.55±0.05	1.50±0.05
<b>D</b> <sub>1</sub>	-	-	-	-	1.00±0.10
E	1.75±0.05	1.75±0.05	1.75±0.05	1.75±0.05	1.75±0.10
F	3.50±0.05	3.50±0.05	3.50±0.05	3.50±0.05	3.50±0.05



Size	0402, 0603, 0805					
Reel size	7"	10"	13"			
С	13.0+0.5/-0.2	13.0+0.5/-0.2	13.0+0.5/-0.2			
<b>W</b> <sub>1</sub>	8.4+1.5/-0	8.4+1.5/-0	8.4+1.5/-0			
Α	178.0±0.10	250.0±1.0	330.0±1.0			
N	60.0+1.0/-0	100.0±1.0	100±1.0			

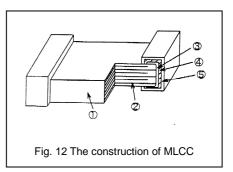




- a. Customer name
- b. WTC order series and item number
- c. Customer P/O
- d. Customer P/N
- e. Description of product
- f. Quantity
- g. Bar code including quantity & WTC P/N or customer
- h. WTC P/N
- i. Shipping date
- j. Order bar code including series and item numbers
- k. Serial number of label

#### Constructions

No.	Na	me	NP0*	NP0	
1	Ceramic	material	CaZrO <sub>3</sub> / BaTiO <sub>3</sub> based		
2	Inner el	ectrode	AgPd alloy	Ni	
3		Inner layer	Ag	Cu	
4	Termination	Middle layer	Ni		
5		Outer layer	Sn		



\* Partial NP0 items are with Ag/Ni/Sn(NME) terminations, please ref to product range for detail.

#### Storage and handling conditions

- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions.
- (2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

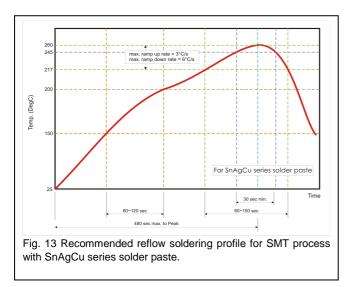
#### Cautions:

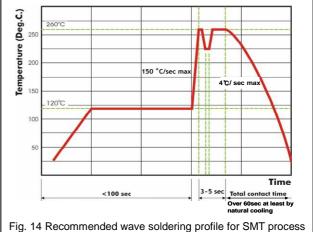
- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.



#### Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of  $N_2$  within oven are recommended.





with SnAgCu series solder.